Abstracts

Harmonical Characterization of a Microstrip Bend via the Finite Difference Time Domain Method

N. Feix, M. Lalande and B. Jecko. "Harmonical Characterization of a Microstrip Bend via the Finite Difference Time Domain Method." 1992 Transactions on Microwave Theory and Techniques 40.5 (May 1992 [T-MTT]): 955-961.

A 90° Microstrip bend is characterized using a Time-Frequency method based on the Finite Difference Time Domain (FDTD) method. Time evolution of the currents generated by FDTD are Fourier transformed to lead to S-parameters and radiated powers characteristic of the microstrip bend. The method for calculating both radiation and surface wave losses is developed in this paper for microstrip structures. Then, the results of the 90° microstrip bend are compared with the results of the mitered microstrip bend.

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